DESIGN OBJECTIVES

The product described in this document has not been fully tested to ensure conformance to the requirements outlined below. Therefore, AMP (Japan) Ltd makes no representation or warranty, express or implied, that the product will comply with these requirements. Further, AMP (Japan), Ltd. may change these requirements based on the results of additional testing and evaluation. Contact AMP Engineering for further details.

In case when "product specification" is referred to in this document, it should be read as "design objectives" for all times as applicable

1. Scope:

This specification covers requirements for product performance and test methods of stacking connector of the following part numbers.

Product Nos.	Descriptions	Type of Stacking		
X-173146-X	Post Heder Assembly	For stacking a top or a bottom board		
X-173145-X	Receptacle Assembly	For stacking intermediate boards		
	Receptacle Assembly (Short Type)	For stacking a top or a bottom board		
X-173144-X	Post Hood	For stacking intermediate boards		

Fig. 1

- (1) The PCB applied combination with these connectors, can make number of printed circuit boards stacked in parallel with each other to connect the circuits electrically.
- (2) The product connectors can be applied to the printed circuit boards having thickness of 1.6mm.
- (3) The post headers and the receptacle assemblies (short type) are used for stacking a top or a bottom board, and the receptacle assemblies (long type) and the post hoods are used to stacking intermediate boards.

2. Applicable Documents:

The following standard and specifications form part of this specification to the extent specified herein.

JIS C 5420	General Rules of Connectors for Printed Wiring Boards
MIL-STD-202	Test Methods for Electronic and Electric Component Parts
MIL-G-45204	Gold Plating, Electrode Deposited
QQ-N-290	Nickel Plating (Electrodedeposted)

- 3. Material and Finish:
- 3.1 Receptacle Contact:
 - (1) Material: CA 725 (Nickel-Copper Alloy)
 - (2) Finish: Overall Nickel Underplate.... 1.3 μm min.
 Long Type Contact Area Gold Plating 0.2 μm min.

(Mating)

Action Area Gold Flash

Post Area Gold Plating 0.2 µm min.

Short Type Contact Area Gold Plating 0.2 μm min.

(Mating)

Other Areas Tin-Lead Plating 1 - 2.5 µm

- 3.2 Post Contact
 - (1) Material: CA 725

CA 725 (Nickel-Copper Alloy)

(2) Finish: Overall Nickel Underplate.... 1.3 μm min.

Post Contact Area, Gold Plating 0.2 µm min.

Action AreaTin-Lead Plating 1 - 2.5 µm min.

- 3.3 Receptacle Housing:
 - (1) Material:

Polybuthylene-Terephthalate (PBT), Glass-filled 15%,

Molded Resin

- (2) Flammability: UL94V-0
- 3.4 Post Header Housing:
 - (1) Material: H

Polybuthylene-Terephthalate (PBT), Glass-filled 15%,

Molded Resin

- (2) Flammability: UL94V-O
- 3.5 Post Hood Housing:

(1) Material: Polybuthylene-Terephthalate (PBT), Glass-filled 15%,

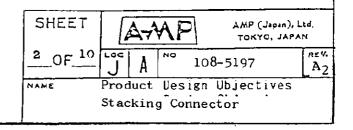
Molded Resid

- (2) Flammability: UL94V-O
- 4. Appearance and Color:
- 4.1 Appearance:

Connector shall have normal appearance without defects such as flaw, cracks, deformation, blister, dirt and burrs, that are detrimental to connector functions and merchandising cosmetic value.

4.2 Color:

The color of the housing shall be black.



- Product Design Feature, Construction and Dimensions:
 Product design feature, construction and dimensions shall be conforming to the applicable product drawing(s).
 - (1) Number of Positions:

 The connectors of 26, 30, 34, 40, 50 and 60-Pos. are available in 6 types.
 - (2) Centerline Spacing:

 The centerline spacing is 2.54mm with 2.54mm row distance.
 - (3) Applicable Printed Circuit Board:

 Applicable printed circuit board shall have thickness of 1.6 -0.13mm, containing glass-fiber and epoxy material.
- 6. Performance:
- 6.1 Ratings:

(1) Current Rating:

.1.5A max.

(2) Voltage Rating:

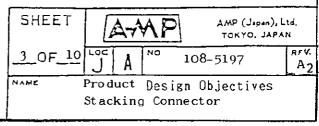
250V AC max.

(3) Temperature Rating: $-25^{\circ}C \sim +85^{\circ}C$

6.2 Electrical Performance Requirements:

Test Items	Performance Requirements	Test Methods
Termination Resistance: (Low Level) Para. 6.2.1	25mΩ max. (Initial) 30mΩ max. (Final)	Measurements shall be made according to Method 307 of MIL-STD-202, with receptacle mated with post header that has been mounted on PCB as shown in Fig. 7. Use test current of open circuit voltage of 50mV max. with closed circuit current of 50mA max.
Insulation Resistance: Para. 6.2.2	5,000MΩ min. (Initial) 1,000MΩ min. (Final)	Measurements shall be made according to Condition "A", Method 302 of MIL-STD-202 (100V -10%), between adjacent contacts in the unmated connector.
Dielectric Strength: Para. 6.2.3	No insulation breakdown nor flashover shall occur.	Test shall be made according to Method 30l of MIL-STD-202, by applying test potential between adjacent contacts. Test Voltage shall be 1,000V (r.m.s.) AC, and hold the voltage for 1 minute.

Fig. 2



2	6.3 Mechanical	Perfor	mance Requ	irements:			
3-5197	Test Items	Perfo	rmance Re	quirements	Test Methods		
108-	Connector Insertion/ Extraction Force:	No. of Insertion Extraction Force kg (Max.) kg (Min.)			A pair of post neader and re-		
변,	Para. 6.3.1	26	4-7	0.78	and unmated at a rate of 100mm a		
NUMBER		30	5.4	0.9	minute maximum after properly se ting on tensile testing machine.		
-		34	6.1	1.02	The force required to mate and to unmate the connector, shall		
_		40	7.2	1.2	be measured and recorded.		
Release		50	9.0	1.5			
ele		60	10.8	1.8			
CLASSIFICATION R	Contact Retention Force: Para. 6.3.2	500 Post H	acle Conne O g min pe eader: Okg min. pe	r Contact	A contact loaded in a connector shall be axially pulled at a rat of 100mm a minute maximum, by using a force gage to measure the force required to dislodge the contact from connector cavity		
	Insertion Force of 10.5 kg max. Action Pin: Para. 6.3.3				Each pin shall be axially inserted in PCB for the test specified in Fig. 2 with the use of a force gage to make measurement of insertion force.		
	Retention Force of Action Pin: Para. 6.3.4	ction Pin: ara. 6.3.4			Each pin mounted on PCB for the test, specified in Fig. 2, shall be perpendicularly pushed from the side opposite to the insertion with the use of a force gage to make measurements of retention force.		
			Fig	. 3			
	6.4 Physical P	erformar	ce Require	ements			
	Test Items	Perfor	mance Regu	irements	Test Methods		
	Durability: Para. 6.4.1	ities, nector evident Low leve sistance 6.2.1. Insertic	nce: No abdetrimentafunctions el terminaeshall me on/extract	Repeat insertion/extraction test conditioning for 50 cycles, in the same manner as specified in Para. 6.3.1.			
	Fig. 4 (T	(To be continued) SHEET AMP (Jack Tokyo, 4 OF 10 Product Design Ubjective Stacking Connector					

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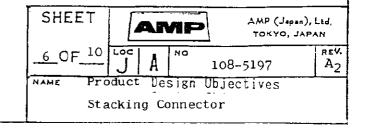
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`	Test Items	Performance Requirements	Test Methods
ררייזווריווחא זיכדממפ	Vibration: Para. 6.4.2	Appearance: No abnormalities detrimental to connector functions shall be evident. Discontinuity of Circuit: No electrical discontinuity greater than 1 microsecond shall take place in the tested circuit during the vibration. Termination Resistance, Low Level: Low level termination resistance shall meet Para. 6.2.1.	The test samples are prepared by mating the contact-loaded receptacle connector mounted on a PCB. Test shall be conducted in accordance with specified Test Method 201Å of MIL-STD-202, with all the contacts series-wired and 100 mÅ being applied to the test circuit during the test. (See Fig. 9.) The test vibration shall be as follows. Frequency: Sweeping to change 10-55-10 Hz, reciprocating one cycle a minute. Maximum Amplitude: 1.52mm both sides Direction of Vibration: Three axial directions (X. Y & Z) Duration: Two hours each direction, 6 hours in total
	Solderability: Para. 6.4.3	Appearance: More than 95% of the tested surfaces shall appear in continuously sufficient coverage of fresh solder, without concentrated pinholes and voids whose total area shall not exceed 5% of the total tested surfaces.	cordance with Test Method 208 of MIL-STD-202, by immersing the sample in the soldering tub which is controlled at 230 +5°C, for
	Soldering Heat Resistivity: Para. 6.4.4	Appearance: After test conditioning, ill affections such as loose of contacts, deterio- ration of insulation and physical damage etc., shall be not evident.	Test shall be conducted in accordance with Method 210 of MIL-STD-202, by immersing the sample in the soldering tub, which is controlled at 260 +5°C. The duration of immersion shall be 10-1 seconds, and the speed of putting into and takup from shall be at a rate of 2.54mm-0.64mm/second.

(To be continued)

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- 7. Test Conditions:
- 7.1 Environmental Conditions:

Unless otherwise specified, all the tests shall be performed in any combination of the following test conditions.

Temperature:

 $15 \sim 35^{\circ}$ C

Relative Humidity

45 ~ 75%

Atmospheric Pressure:

 $650\sim$ 800mmHg

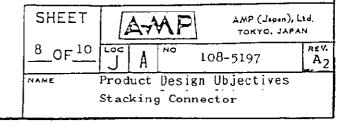
- 7.2 Test Specimens:
- 7.2.1 All the samples to be employed by the tests, shall be confirmed for conformance to the applicable product drawing(s).
- 7.2.2 Unless otherwise specified, all the printed circuit boards to be employed for the tests, shall be conforming to the specification specified in Fig. 8.
- 7.2.3 Unless otherwise specified, no sample shall be reused.

8.	Test	Sequence:
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5197	Test Items	Para- graph	Sample Groups							
108-5197		No.	1	2	3	4	5	6	7	8
	Appearance	4.1		1	1	1	1	1		
	Termination Resistance Low Level	6.2.1		2,4	2,4	2,5,7	2,4			
.	Insulation Resistance	6.2.2						2,5		
ise	Dielectric Strength	6.2.3						3,6		
Release	Connector Insertion/ Extraction Force	6.3.1				3				
	Thermal Shock	6.5.1		3			,			
ICATIO	Heat Resistivity	6.5.2			3					
CLASSIFICATION	Humidity	6.5.3				6		4		
	Durability	6.4.1				4				
	Vibration	6.4.2					3			
l	Contact Retention Force	6.3.2						7		
	Action Pin Insertion Force	6.3.3	1			1	·			
	Action Pin Retention Force	6.3.4	2	5	5	i.	5			
	Solderability	6.4.3							1	
	Soldering Heat Resistivity	6.4.4								1

Fig. 6

- 1. The numbers in the columns indicate the sequence in which tests are performed.
- 2. Sample Group 1 consists of action pins and printed circuit boards conforming to the specification specified in Fig. 8.
- 3. Sample Groups 2 and 3 constist of connector mounted on PCB and PCB to which action pins only are mounted.
- 4. Groups 4 and 5 consist of connector mounted on PCB.
- 5. Group 6 consists of samples not mounted on PCB.
- 6. Each Sample Group consists of 4 sets of connectors.



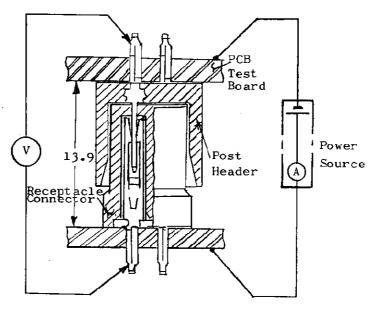
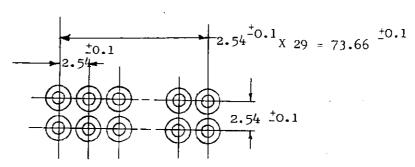


Fig. 7 Measurment of Termination Resistance (Low Level)



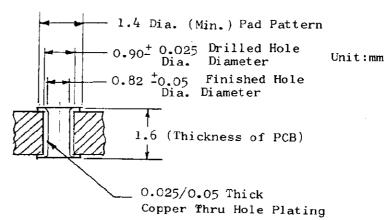
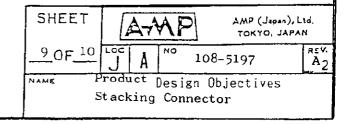


Fig. 8 PCB Test Board Hole Design



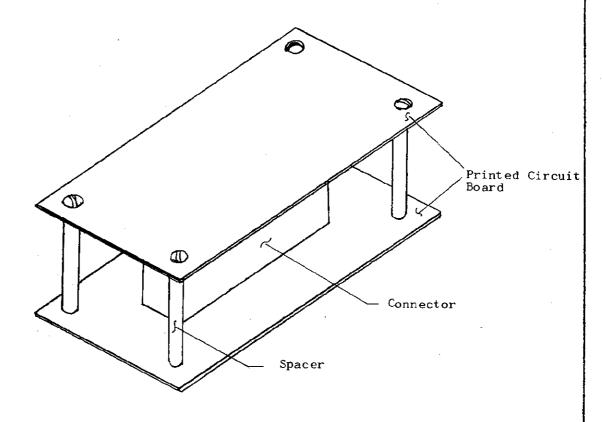


Fig. 9 Mounting Test Connector Sample for Vibration Test

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